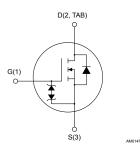


N-channel 600 V, 0.95 Ω typ., 5 A MDmesh™ DM2 Power MOSFET in an IPAK package



IPAK



Features

Order code	V _{DS}	R _{DS(on)} max.	l _D	P _{TOT}
STU6N60DM2	600 V	1.10 Ω	5 A	60 W

- Fast-recovery body diode
- Extremely low gate charge and input capacitance
- · Low on-resistance
- 100% avalanche tested
- · Extremely high dv/dt ruggedness
- · Zener-protected

Applications

· Switching applications

Description

lectronics sales office

This high-voltage N-channel Power MOSFET is part of the MDmesh $^{\text{TM}}$ DM2 fast-recovery diode series. It offers very low recovery charge (Q_{rr}) and time (t_{rr}) combined with low $R_{DS(on)}$, rendering it suitable for the most demanding high-efficiency converters and ideal for bridge topologies and ZVS phase-shift converters.

Product status link				
STU6N60DM2				
Product summary				
Order code	STU6N60DM2			
Marking	6N60DM2			
Package	IPAK			
Packing	Tube			

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1 Electrical ratings

Table 1. Absolute maximum ratings

Symbol	Parameter	Value	Unit
V_{GS}	Gate-source voltage	±25	V
I_	Drain current (continuous) at T _{case} = 25 °C	5	^
I _D	Drain current (continuous) at T _{case} = 100 °C	3.2	Α
I _{DM} ⁽¹⁾	Drain current (pulsed)	20	Α
P _{TOT}	Total dissipation at T _{case} = 25 °C	60	W
dv/dt ⁽²⁾	Peak diode recovery voltage slope	50	V/ns
dv/dt ⁽³⁾	MOSFET dv/dt ruggedness	50	V/IIS
T _{stg}	Storage temperature range	-55 to 150	°C
T _j	Operating junction temperature range	-55 to 150	

- 1. Pulse width is limited by safe operating area.
- 2. $I_{SD} \le 5$ A, di/dt = 900 A/ μs ; V_{DS} peak $< V_{(BR)DSS}$, $V_{DD} = 480$ V.
- 3. $V_{DS} \le 480 \text{ V}.$

Table 2. Thermal data

Symbol	Parameter	Value	Unit
R _{thj-case}	Thermal resistance junction-case	2.08	°C/W
R _{thj-amb}	Thermal resistance junction-ambient	100	C/VV

Table 3. Avalanche characteristics

Symbol	Parameter	Value	Unit
I _{AR} (1)	Avalanche current, repetitive or not repetitive	1.7	Α
E _{AS} (2)	Single pulse avalanche energy	132	mJ

- 1. Pulse width limited by T_{jmax} .
- 2. Starting $T_j = 25$ °C, $I_D = I_{AR}$, $V_{DD} = 50$ V.

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2 Electrical characteristics

(T_{case} = 25 °C unless otherwise specified)

Table 4. Static

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
V _{(BR)DSS}	Drain-source breakdown voltage	V _{GS} = 0 V, I _D = 1 mA	600			V
	Zana mata waltana duain	V _{GS} = 0 V, V _{DS} = 600 V			1	
I _{DSS}	Zero gate voltage drain current	$V_{GS} = 0 \text{ V}, V_{DS} = 600 \text{ V},$ $T_{case} = 125 ^{\circ}\text{C}^{(1)}$			100	μA
I _{GSS}	Gate-body leakage current	V _{DS} = 0 V, V _{GS} = ±25 V			±5	μA
V _{GS(th)}	Gate threshold voltage	$V_{DS} = V_{GS}$, $I_D = 250 \mu A$	3.25	4	4.75	V
R _{DS(on)}	Static drain-source on- resistance	V _{GS} = 10 V, I _D = 2.5 A		0.95	1.10	Ω

^{1.} Defined by design, not subject to production test.

Table 5. Dynamic

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
C _{iss}	Input capacitance		-	274	-	
C _{oss}	Output capacitance	V_{DS} = 100 V, f = 1 MHz, V_{GS} = 0 V	-	15	-	pF
C _{rss}	Reverse transfer capacitance		-	2	-	
C _{oss eq.} (1)	Equivalent output capacitance	V _{DS} = 0 to 480 V, V _{GS} = 0 V	-	25	-	pF
R _G	Intrinsic gate resistance	f = 1 MHz, I _D = 0 A	-	6.5	-	Ω
Qg	Total gate charge	V_{DD} = 480 V, I_D = 5 A, V_{GS} = 0 to 10 V (see Figure 14. Test circuit for	-	6.2	-	
Q _{gs}	Gate-source charge		-	1.8	-	nC
Q _{gd}	Gate-drain charge	gate charge behavior)	-	2.7	-	

^{1.} $C_{\text{oss eq.}}$ is defined as a constant equivalent capacitance giving the same charging time as C_{oss} when V_{DS} increases from 0 to 80% V_{DSS} .

Table 6. Switching times

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
t _{d(on)}	Turn-on delay time	V_{DD} = 300 V, I_{D} = 2.5 A R_{G} = 4.7 Ω , V_{GS} = 10 V (see Figure 13. Test	-	9.2	-	
t _r	Rise time		-	5.6	-	no
t _{d(off)}	Turn-off delay time	circuit for resistive load switching times and Figure 18. Switching time	-	12	-	ns
t _f	Fall time	waveform)	-	19.6	-	

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Table 7. Source-drain diode

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
I _{SD}	Source-drain current		-		5	Α
I _{SDM} ⁽¹⁾	Source-drain current (pulsed)		-		20	Α
V _{SD} (2)	Forward on voltage	V _{GS} = 0 V, I _{SD} = 5 A	-		1.6	V
t _{rr}	Reverse recovery time	I _{SD} = 5 A, di/dt = 100 A/μs, V _{DD} = 60 V (see Figure 15. Test circuit for inductive load switching and diode recovery times)	-	60		ns
Q _{rr}	Reverse recovery charge		-	135		nC
I _{RRM}	Reverse recovery current		-	4.5		Α
t _{rr}	Reverse recovery time	I _{SD} = 5 A, di/dt = 100 A/μs, V _{DD} = 60 V, T _j = 150 °C (see Figure 15. Test circuit for inductive load	-	132		ns
Q _{rr}	Reverse recovery charge		-	429		nC
I _{RRM}	Reverse recovery current	switching and diode recovery times)	-	6.5		Α

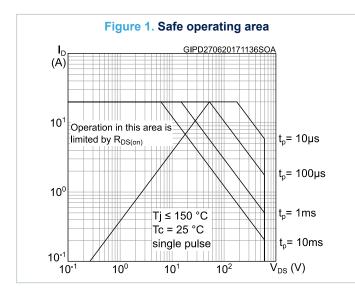
^{1.} Pulse width is limited by safe operating area.

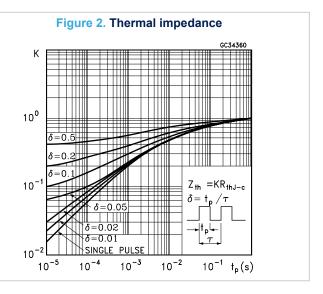
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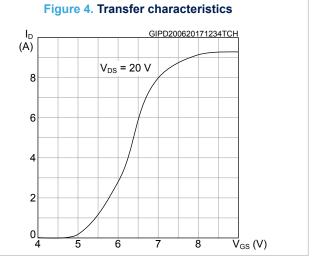
^{2.} Pulse test: pulse duration = $300 \mu s$, duty cycle 1.5%.



2.1 Electrical characteristics (curves)







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Figure 5. Gate charge vs gate-source voltage

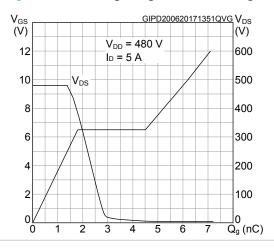


Figure 6. Static drain-source on-resistance

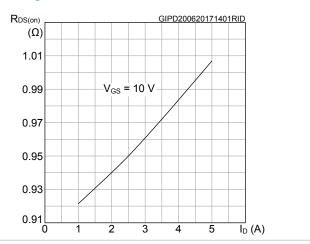


Figure 7. Capacitance variations

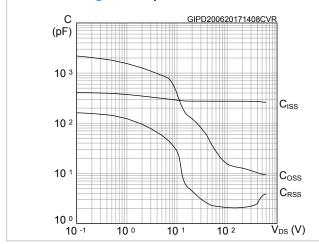


Figure 8. Output capacitance stored energy

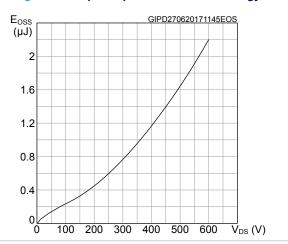


Figure 9. Normalized gate threshold voltage vs temperature

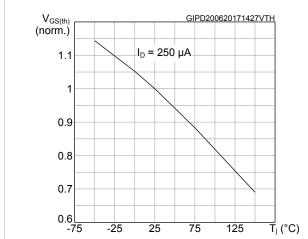
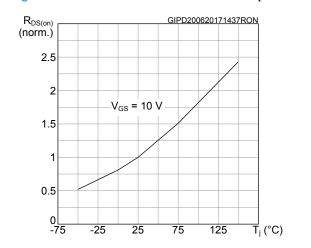


Figure 10. Normalized on-resistance vs temperature



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Figure 11. Source-drain diode forward characteristics

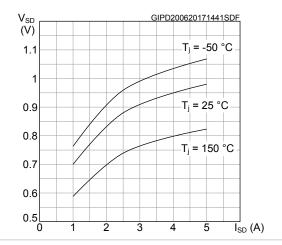
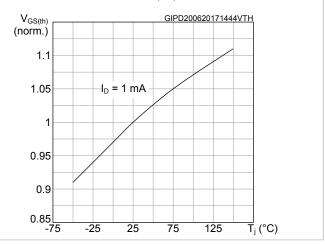


Figure 12. Normalized $V_{(BR)DSS}$ vs temperature





3 Test circuits

Figure 13. Test circuit for resistive load switching times

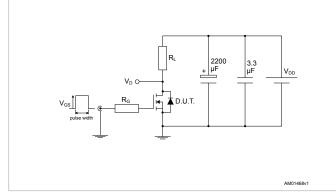


Figure 14. Test circuit for gate charge behavior

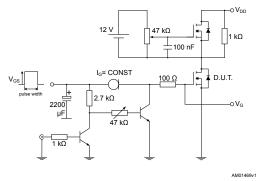


Figure 15. Test circuit for inductive load switching and diode recovery times

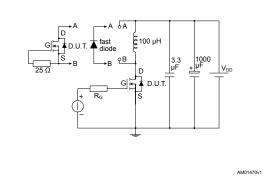


Figure 16. Unclamped inductive load test circuit

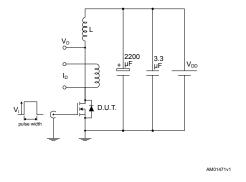


Figure 17. Unclamped inductive waveform

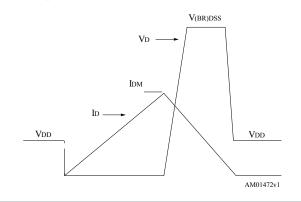
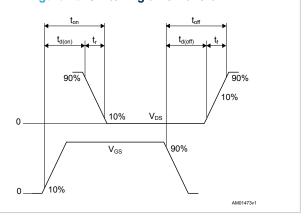


Figure 18. Switching time waveform



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4 Package information

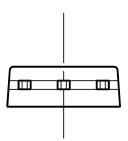
In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK® packages, depending on their level of environmental compliance. ECOPACK® specifications, grade definitions and product status are available at: www.st.com. ECOPACK® is an ST trademark.

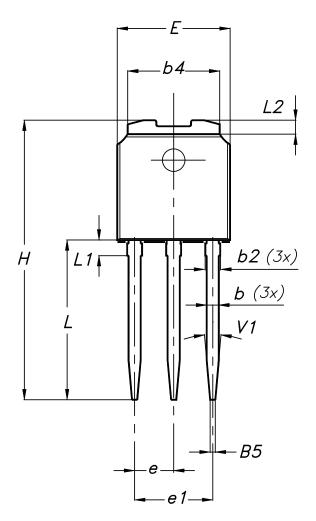
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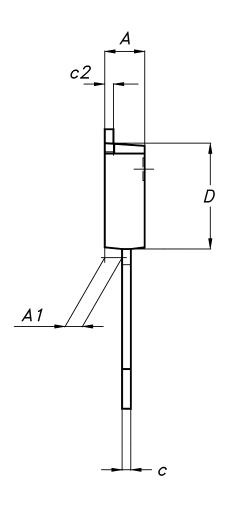


4.1 IPAK (TO-251) type A package information

Figure 19. IPAK (TO-251) type A package outline







0068771_IK_typeA_rev14

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Table 8. IPAK (TO-251) type A package mechanical data

Dim.	mm				
Dim.	Min.	Тур.	Max.		
А	2.20		2.40		
A1	0.90		1.10		
b	0.64		0.90		
b2			0.95		
b4	5.20		5.40		
B5		0.30			
С	0.45		0.60		
c2	0.48		0.60		
D	6.00		6.20		
E	6.40		6.60		
е		2.28			
e1	4.40		4.60		
Н		16.10			
L	9.00		9.40		
L1	0.80		1.20		
L2		0.80	1.00		
V1		10°			

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Revision history

Table 9. Document revision history

Date	Revision	Changes
03-Jul-2017	1	First release
14-Jun-2018	2	Updated Table 5. Dynamic.

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